

**(WO/2005/015121) STYLUS TIP FOR WORKPIECE CONTACTING PROBE**

Biblio. Data	Description	Claims	National Phase	Notices	Documents
------------------------------	-----------------------------	------------------------	--------------------------------	-------------------------	---------------------------

Latest bibliographic data on file with the International Bureau

Publication Number: WO/2005/015121 **International Application No.:** PCT/GB2004/003402
Publication Date: 17.02.2005 **International Filing Date:** 06.08.2004

Int. Class.: G01B 5/016 (2006.01), G01B 7/016 (2006.01)

Applicants: RENISHAW PLC [GB/GB]; New Mills, Wotton-under-Edge, Gloucestershrie GL112 8JR (GB) (*All Except US*).

LEWICKA-SCHAFER, Magdalena [GB/GB]; 44 Hopkins Close, Thornbury, Bristol South, Gloucestershire BS35 2PX (GB) (*US Only*).

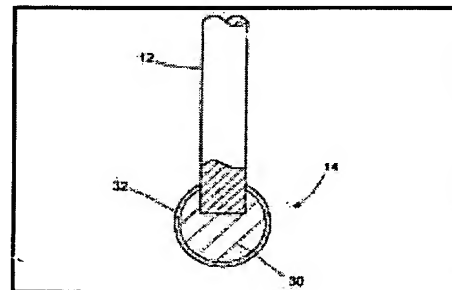
Inventor: LEWICKA-SCHAFER, Magdalena [GB/GB]; 44 Hopkins Close, Thornbury, Bristol South, Gloucestershire BS35 2PX (GB).

Agent: JACKSON, John, Timothy; Renishaw plc, Patent Department, New Mills, Wotton-under-Edge, Gloucestershire GL12 8JR (GB).

Priority Data: 0318388.6 06.08.2003 GB

Title: STYLUS TIP FOR WORKPIECE CONTACTING PROBE

Abstract: A stylus (12) for a workpiece contacting probe has a tip (14) which comprises a self-lubricating or low friction material, in order to inhibit debris generation or adhesive wear (pick up) as the tip scans a workpiece surface. Various materials are described, including composites having a solid state lubricant incorporated into a dimensionally stable microstructure. The tip (14) may be made entirely of such a composite, or may have a substrate (30) with a coating (32) of the self-lubricating or low friction material. Suitable materials are silicon carbide or silicon nitride containing free graphite hexagonal boron nitride, molybdenum sulphide or metallic tin, furthermore silicon carbide/nitride impregnated with PTFE, or annealed boron carbide.



Designated States: AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.
African Regional Intellectual Property Org. (ARIPO) (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW)
Eurasian Patent Organization (EAPO) (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM)
European Patent Office (EPO) (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI, SK, TR)
African Intellectual Property Organization (OAPI) (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

Publication Language:

English (EN)

Filing Language:

English (EN)